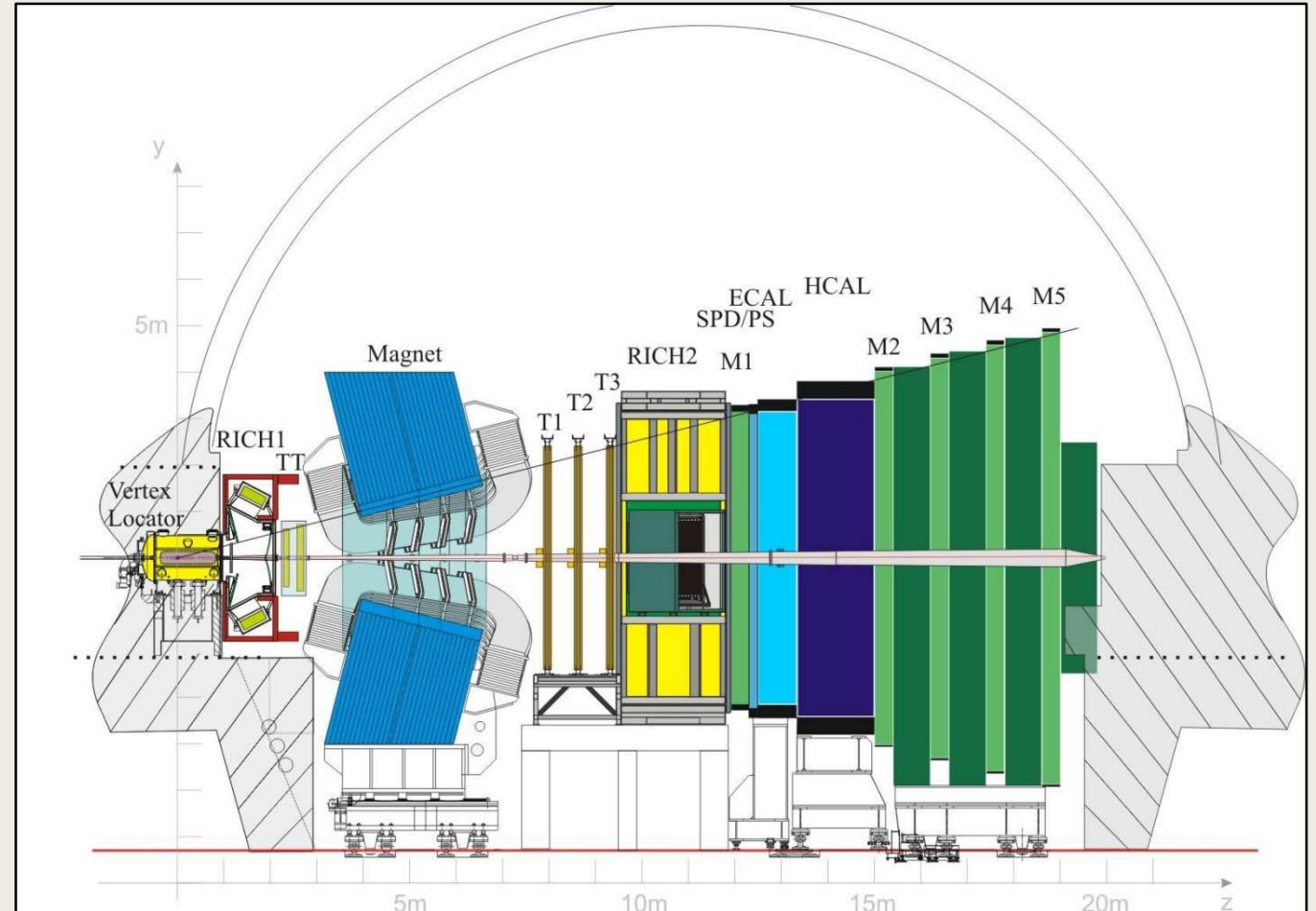


Relative Branching Fraction Measurements of $B \rightarrow 3h$ Decays

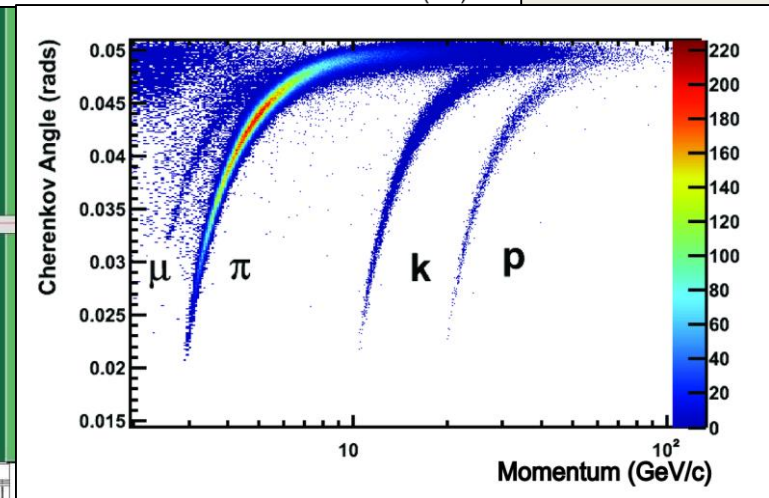
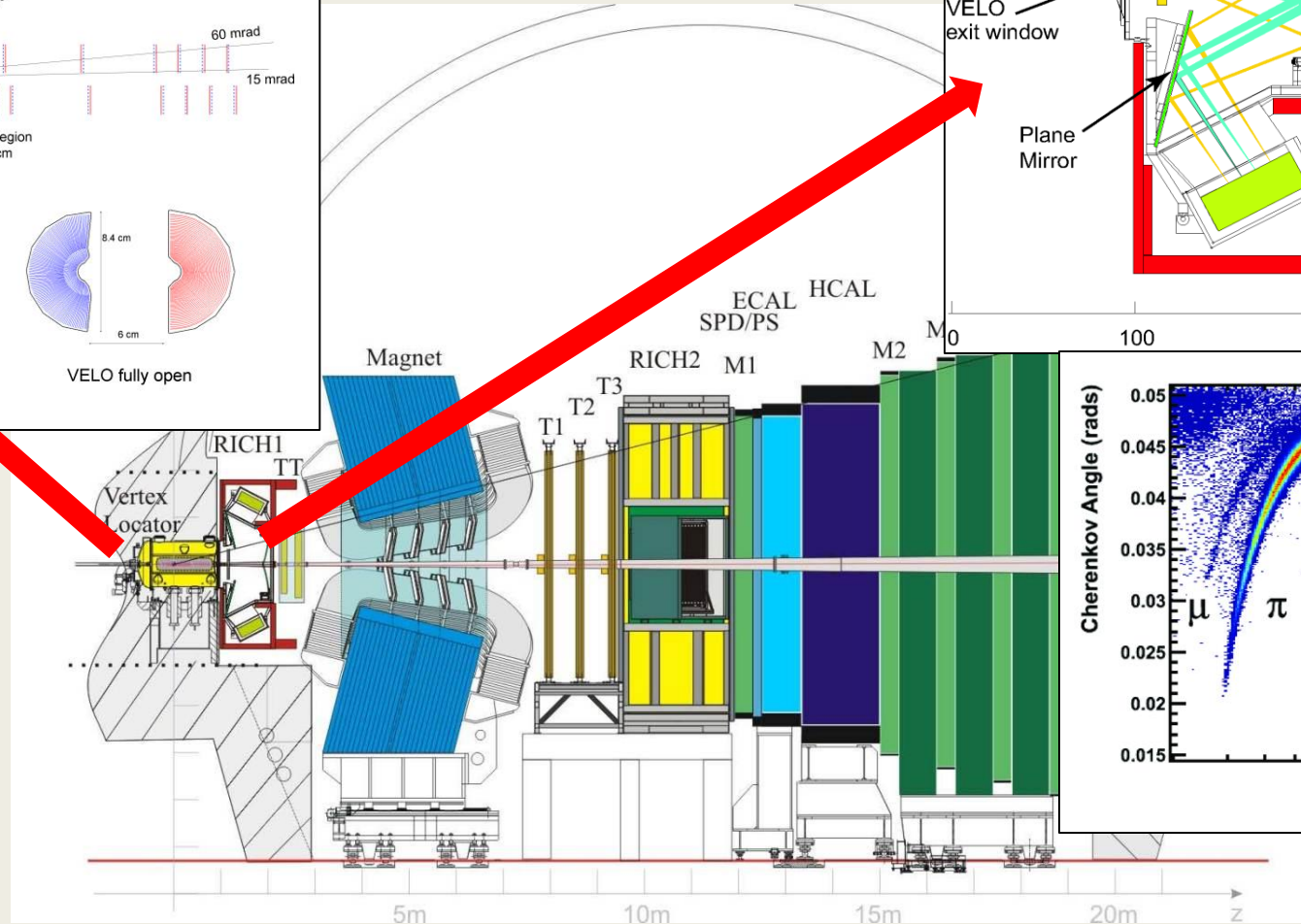
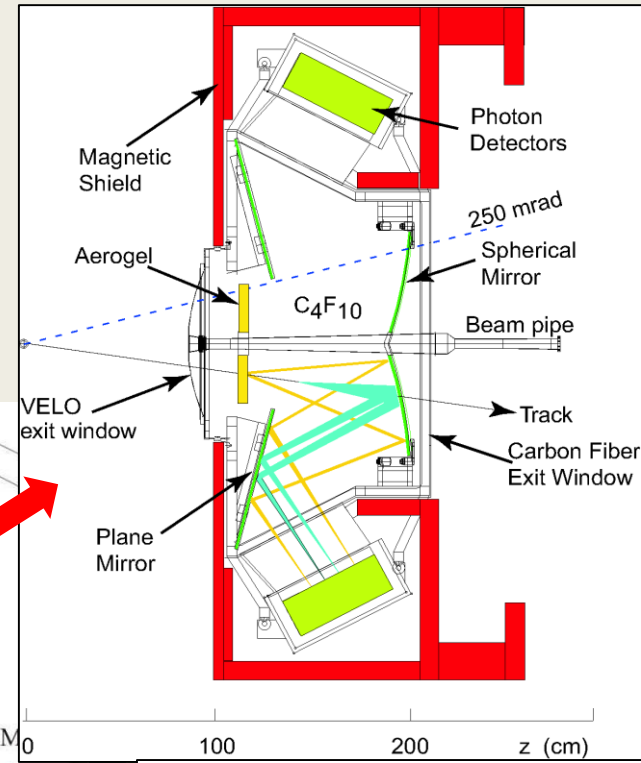
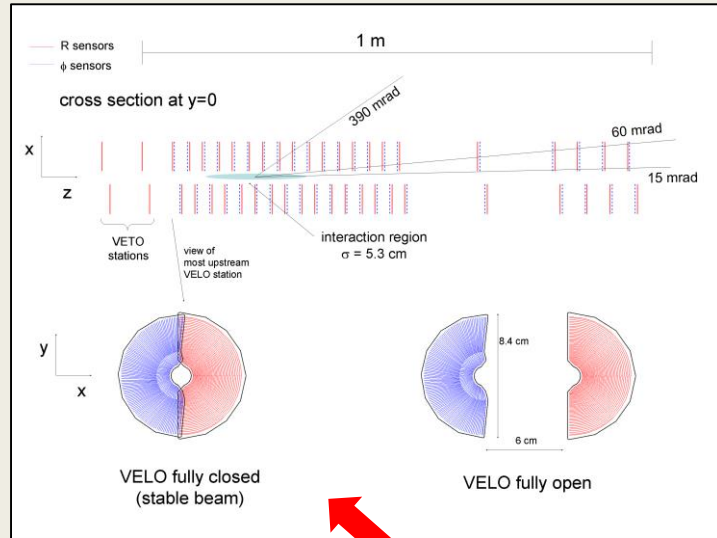
Cayo Costa Sobral, on behalf of the LHCb collaboration
University of Warwick

Outline

- The LHCb detector
- Charmless $B \rightarrow 3h$ decays
- Relative BF measurement:
 - Analysis strategy
 - Event selection
 - Preliminary Run 1 results
 - Plan for completion

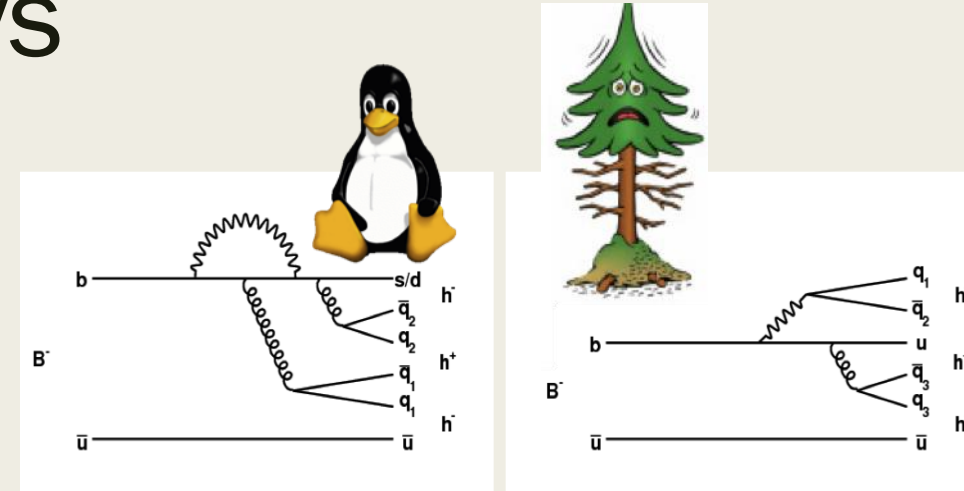


The LHCb Detector

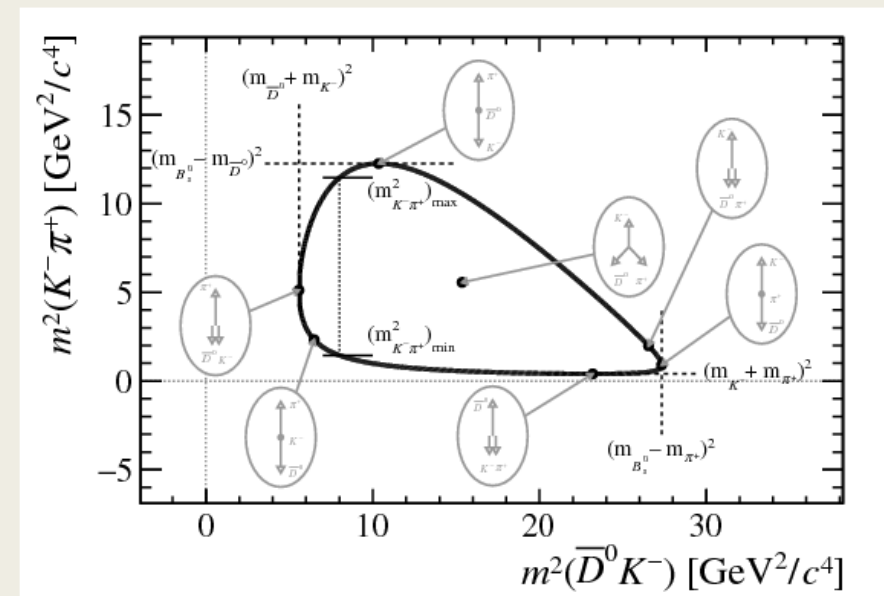


Charmless $B \rightarrow 3h$ decays

- Tree-level $b \rightarrow u$ amplitudes have comparable size to loop-level $b \rightarrow d, s$ contributions
 - Amplitudes can interfere leading to large CP violation effects
 - New Physics can contribute to loops – extra CPV sources



- Decays of a spin-0 particle to three spin-0 particles can be described by the **Dalitz plot** (DP)
 - Can be used to study resonant structures + CP violation effects in this type of decay
 - DP analyses can extract, in principle, all observable information about the decay:
 - Usually measure fit fractions (FF) and A_{CP}
 - $BF(B \rightarrow Rh) = BF(B \rightarrow h'h''h) \cdot FF_R$



J. Back et al., [arXiv:1711.09854](https://arxiv.org/abs/1711.09854)

Charmless $B \rightarrow 3h$ decays

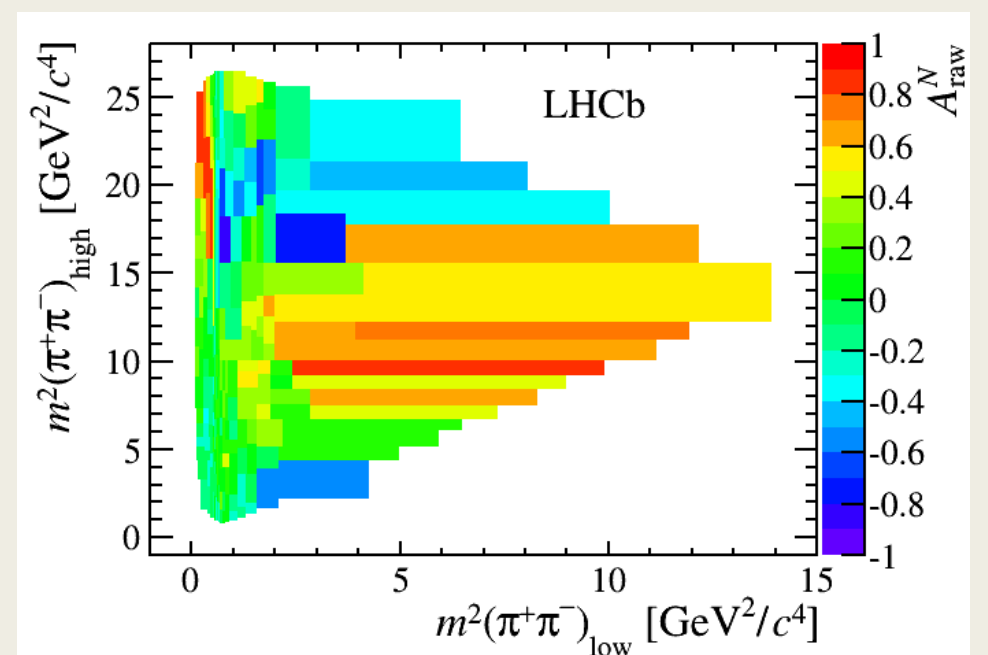
- Previous LHCb analysis measured A_{CP} :
 - Model-independent – no info on contributing resonances
 - Non-zero inclusive A_{CP} ranging $[2.8 - 5.6]\sigma$
 - Areas of phase space where large A_{CP} observed
- Next steps:
 - Amplitude analyses (AA) of each individual mode
 - $B \rightarrow 3h$ relative BF measurements (**this talk**)
- This analysis:
 - Improved BF measurement + fit fractions from AAs
 - BFs for resonant contributions
 - Improve on previous event selection:
 - Include new information – isolation variables
 - Establish Run 2 optimisation

$$A_{CP}(B^\pm \rightarrow K^+K^+K^-) = -0.036 \pm 0.004 \pm 0.002 \pm 0.007$$

$$A_{CP}(B^\pm \rightarrow \pi^\pm K^+K^-) = -0.123 \pm 0.017 \pm 0.012 \pm 0.007$$

$$A_{CP}(B^\pm \rightarrow K^\pm \pi^+ \pi^-) = +0.025 \pm 0.004 \pm 0.004 \pm 0.007$$

$$A_{CP}(B^\pm \rightarrow \pi^\pm \pi^+ \pi^-) = +0.058 \pm 0.008 \pm 0.009 \pm 0.007$$



R. Aaij et al., Phys. Rev. D **90**, 112004 (2014)

Analysis strategy

- Measure $B \rightarrow 3h$ BF, relative to $B \rightarrow KKK$
 - Plan to also report ratios relative to the other modes
- Use 2011+2012 (Run 1) and 2015+2016 (Run 2) data
- Treat the two runs separately:
 - Independent selection optimisation
 - Determine ratios separately
 - Combine results once ratios+uncertainties calculated

PID selection

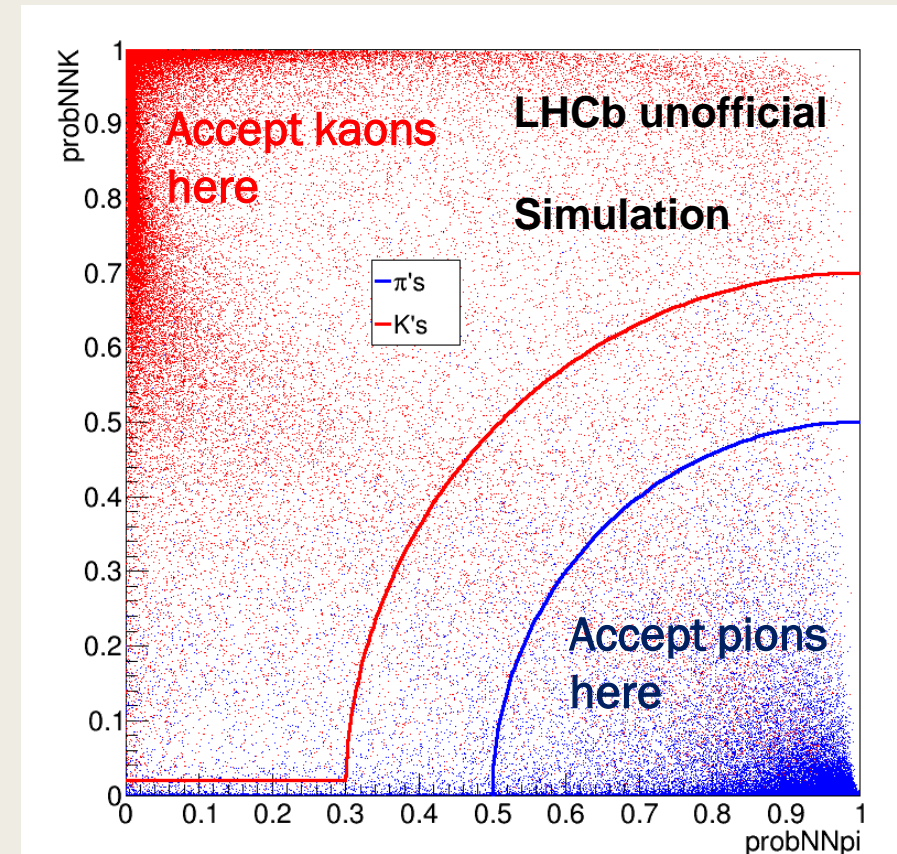
- Mis-identified $B \rightarrow 3h$ are important backgrounds
- Optimise PID on these cross-feed backgrounds only
- Use circular cuts in PID parameter space

- Kaons: $\sqrt{p_{\text{kaon}}^2 + (p_{\text{pion}} - 1)^2} > r_K^2$
- Pions: $\sqrt{p_{\text{kaon}}^2 + (p_{\text{pion}} - 1)^2} < r_\pi^2$
- For kaons, also require $p_{\text{kaon}} > 0.02$
- Impose the constraint $r_K^2 \geq r_\pi^2$

- Optimise cut with the Figure of Merit (FoM):

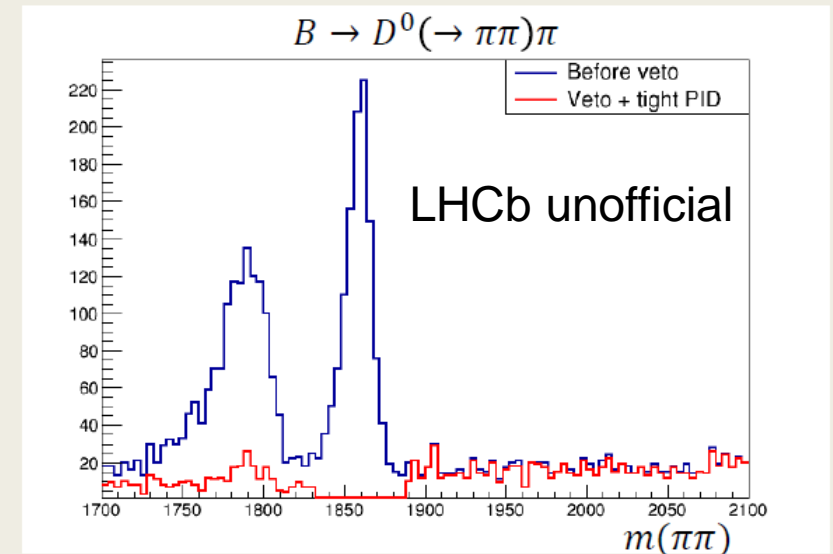
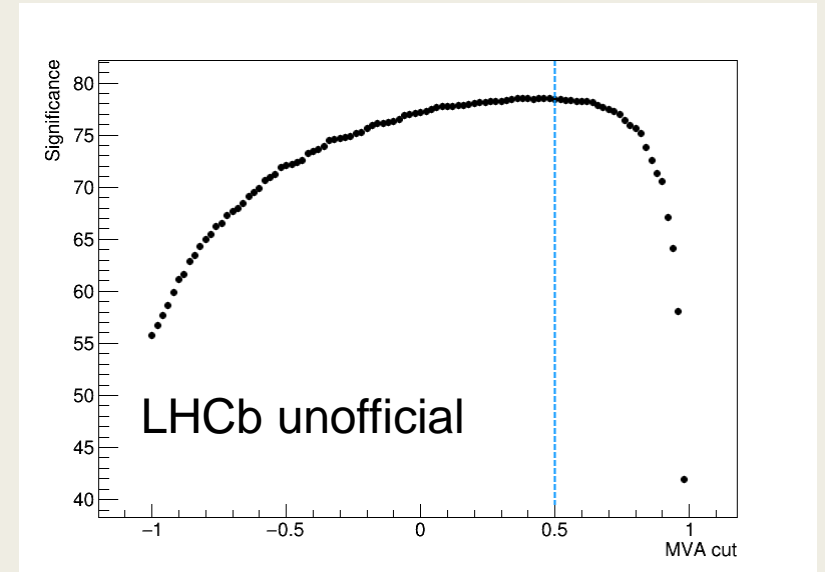
- $$\text{FoM} = \frac{\epsilon_{\text{sig}}}{\sqrt{\epsilon_{\text{sig}} + \sum f \cdot \epsilon_{\text{misID}}}}$$
 - $f = \text{BF}_{\text{misID}} / \text{BF}_{\text{sig}}$

Channel	misID considered
KKK	$\pi KK, K\pi\pi$
πKK	$KKK, K\pi\pi$
$K\pi\pi$	$\pi KK, \pi\pi\pi$
$\pi\pi\pi$	$K\pi\pi$



MVA selection + vetoes

- Use multivariate analysis (MVA) to reduce combinatorial background
 - Neural network using the NeuroBayes algorithm
 - Train using Monte Carlo (MC) sample for signal, high-mass sideband data for background
 - Combination of 7 kinematical+topological input variables
 - Use πKK MC+data to maximise sensitivity to this mode
- Exclude charmed contributions through a veto
 - Veto region $[1830,1890]$ MeV/ c^2 , centred on D^0 mass
 - Also see misID charm contributions
 - Apply tighter PID cuts rather than vetoes in this case

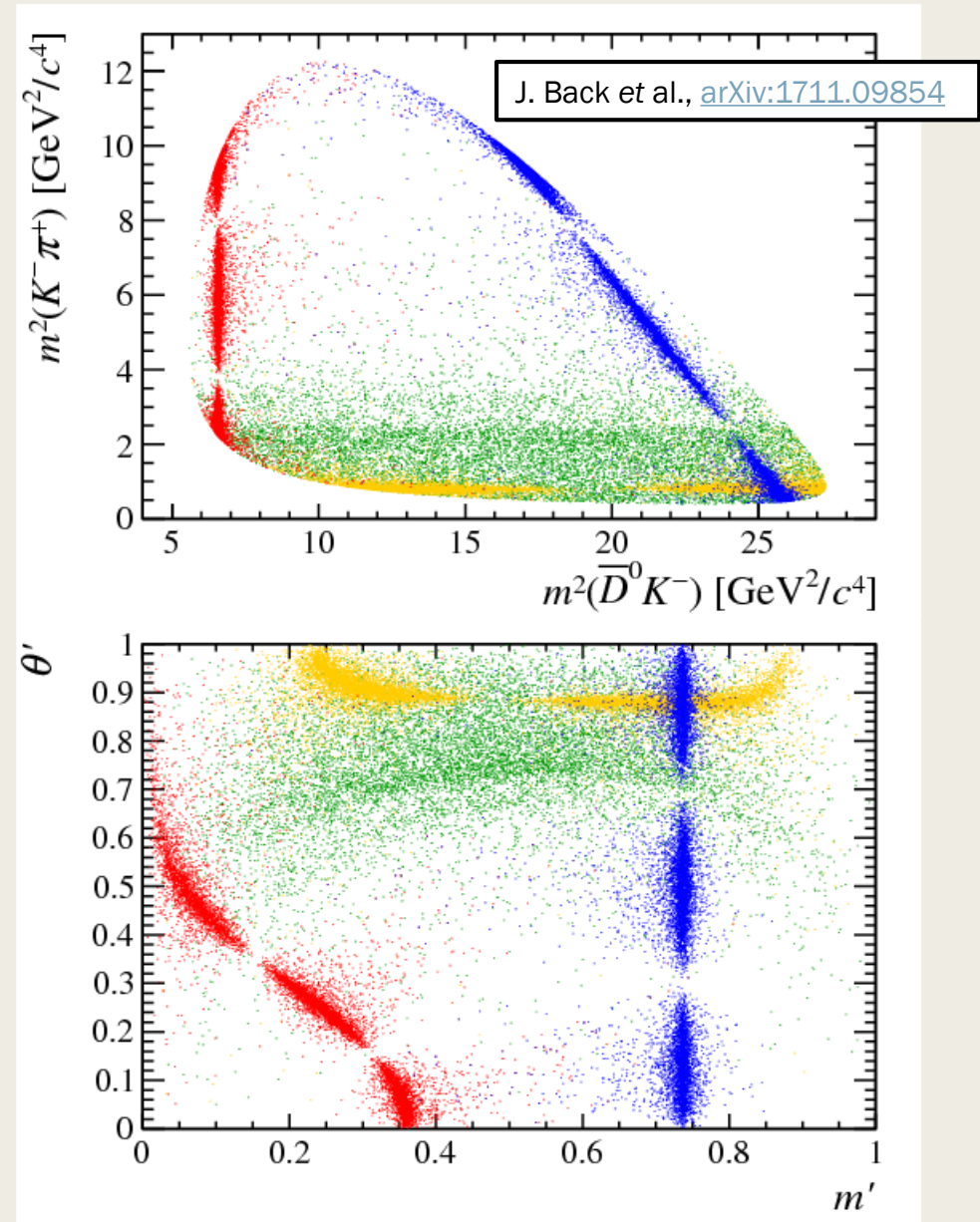


Square Dalitz plot

- Most signal is concentrated along the edges of DP
- Rapid efficiency variation in these regions
- Square DP transformation spreads out these areas

$$m' = \frac{1}{\pi} \arccos \left(2 \frac{m_{ij} - (m_i + m_j)}{m_B - (m_i + m_j + m_k)} - 1 \right),$$

$$\theta' = \frac{1}{\pi} \left(\frac{m_{ij}^2(m_{jk}^2 - m_{ij}^2) - (m_j^2 - m_i^2)(m_B^2 - m_k^2)}{\sqrt{(m_{ij}^2 + m_i^2 - m_j^2)^2 - 4m_{ij}^2 m_i^2} \sqrt{(m_B^2 - m_k^2 - m_i^2)^2 - 4m_{ij}^2 m_k^2}} \right).$$

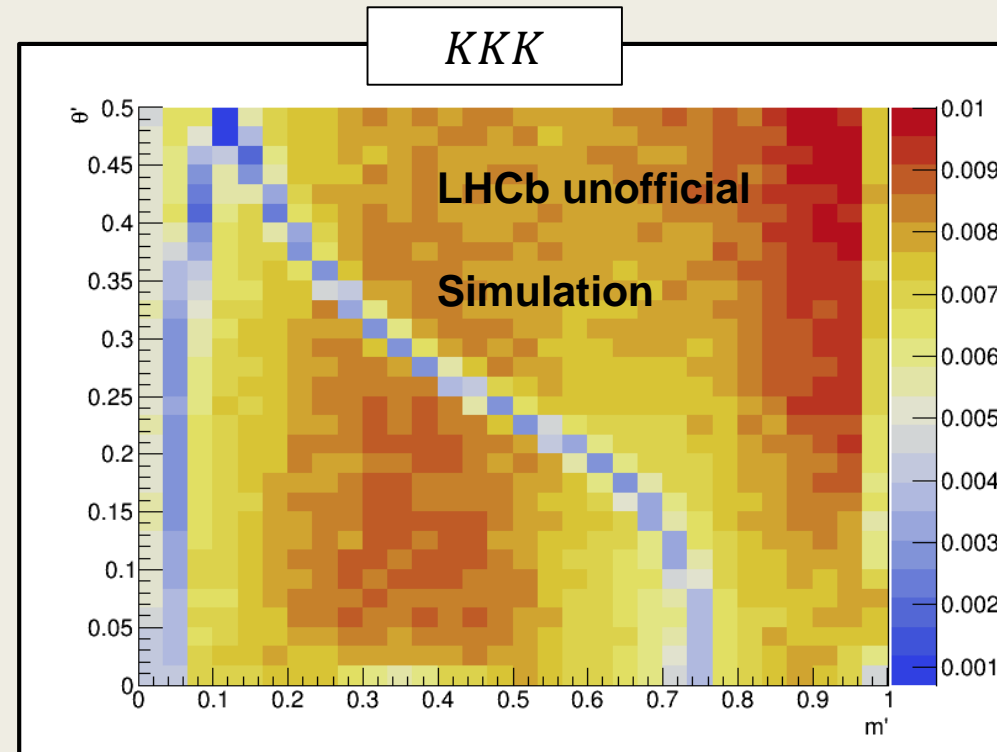


Efficiencies

- Event selection can favour certain areas of the phase space over others
 - Must correct this by calculating selection efficiency as function of DP
- PID efficiencies are obtained through data-driven method
- Geometric + selection efficiencies calculated from MC

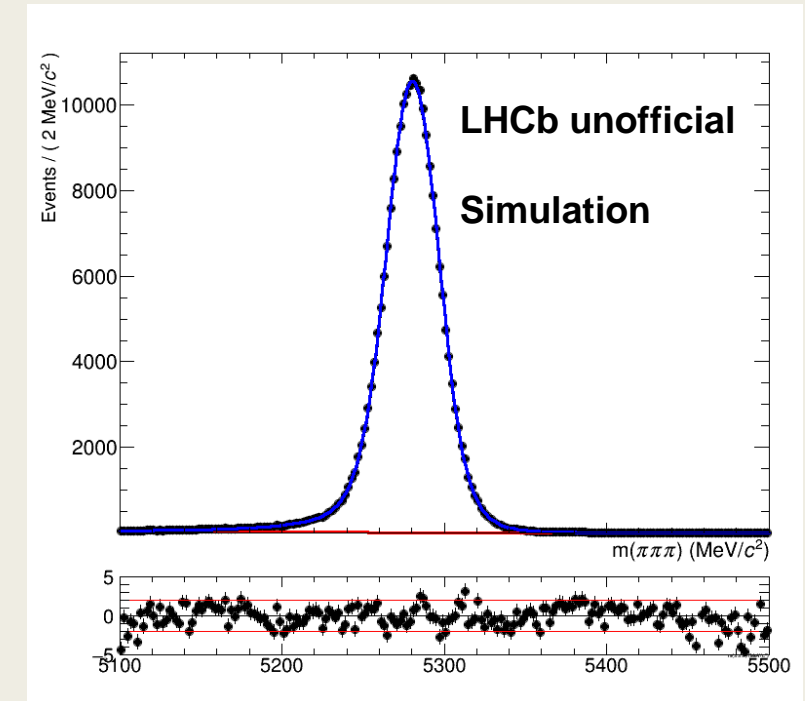
Channel	$\epsilon^{\text{sel+geom}}$ (%)	ϵ^{PID} (%)	ϵ^{tot} (%)
<i>KKK</i>	0.9205 ± 0.0007	76.86 ± 0.17	0.7075 ± 0.0016
<i>KπK</i>	0.8841 ± 0.0007	58.58 ± 0.16	0.5179 ± 0.0015
<i>Kππ</i>	0.8637 ± 0.0007	67.65 ± 0.16	0.5843 ± 0.0015
<i>πππ</i>	0.8137 ± 0.0007	72.49 ± 0.17	0.5898 ± 0.0014

*statistical uncertainties only



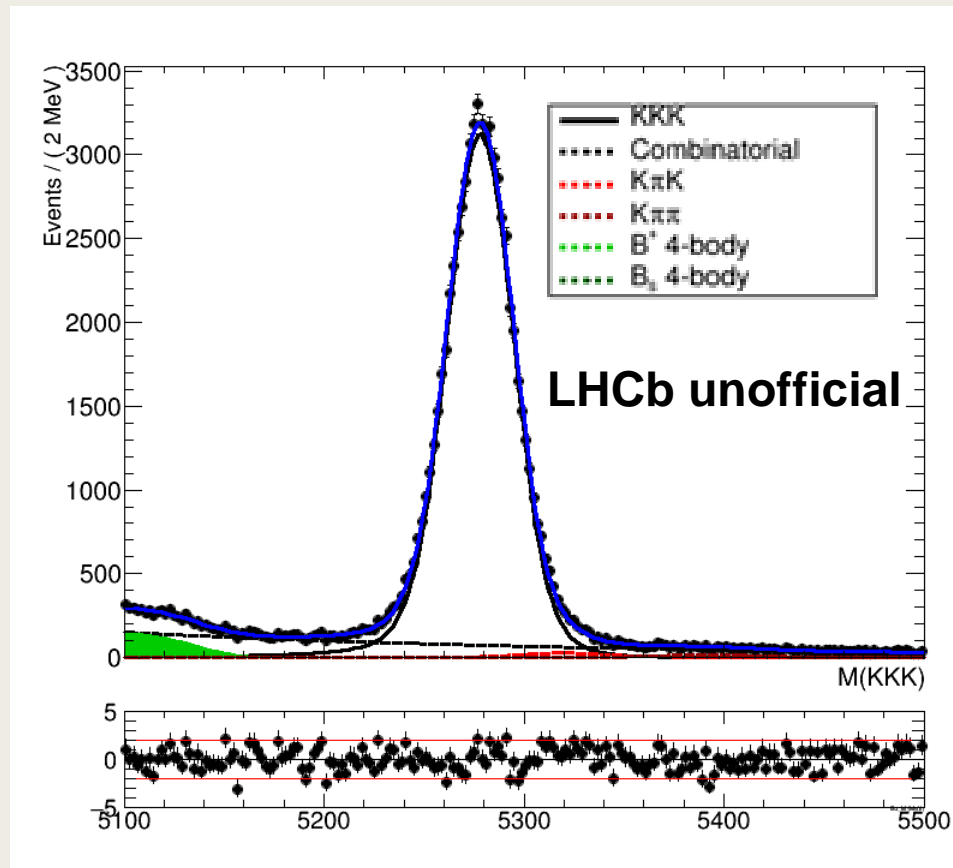
Fit model

- Signal modes – Double Crystal Ball (DCB):
 - Tail parameters fixed to MC fit
 - Width in data fit = width from MC (fixed) \times scale parameter (floating)
 - Peak position floats in data fit – shared between the four modes
- Cross-feed modes – DCB:
 - Reweighted according to physical DP distribution
 - Peak position and tail parameters fixed to MC fit
- Combinatorial – exponential
- Partially reconstructed – ARGUS \otimes Gaussian:
 - Include one PDF for $B^+, B^0 \rightarrow 4\text{body}$ and one for $B_s \rightarrow 4\text{body}$
 - Extra $B \rightarrow \eta' K$ component in the $B \rightarrow K\pi\pi$ model

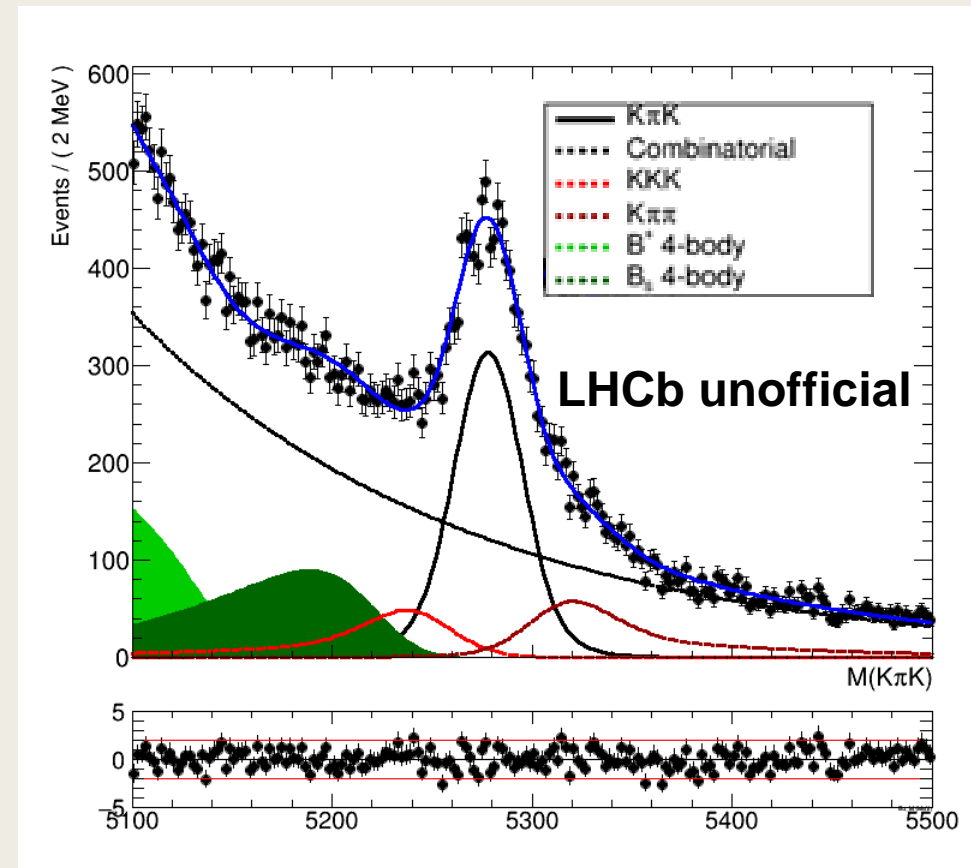


Simultaneous fit

- Perform simultaneous fit of all four signal modes on Run 1 data



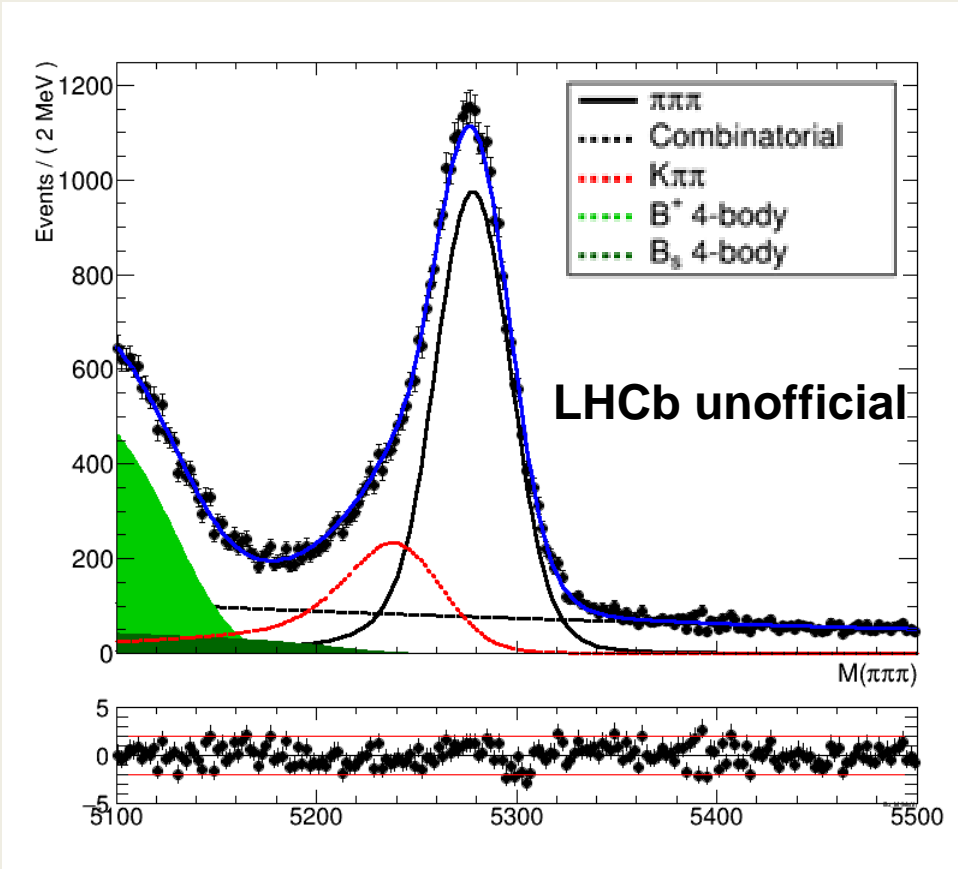
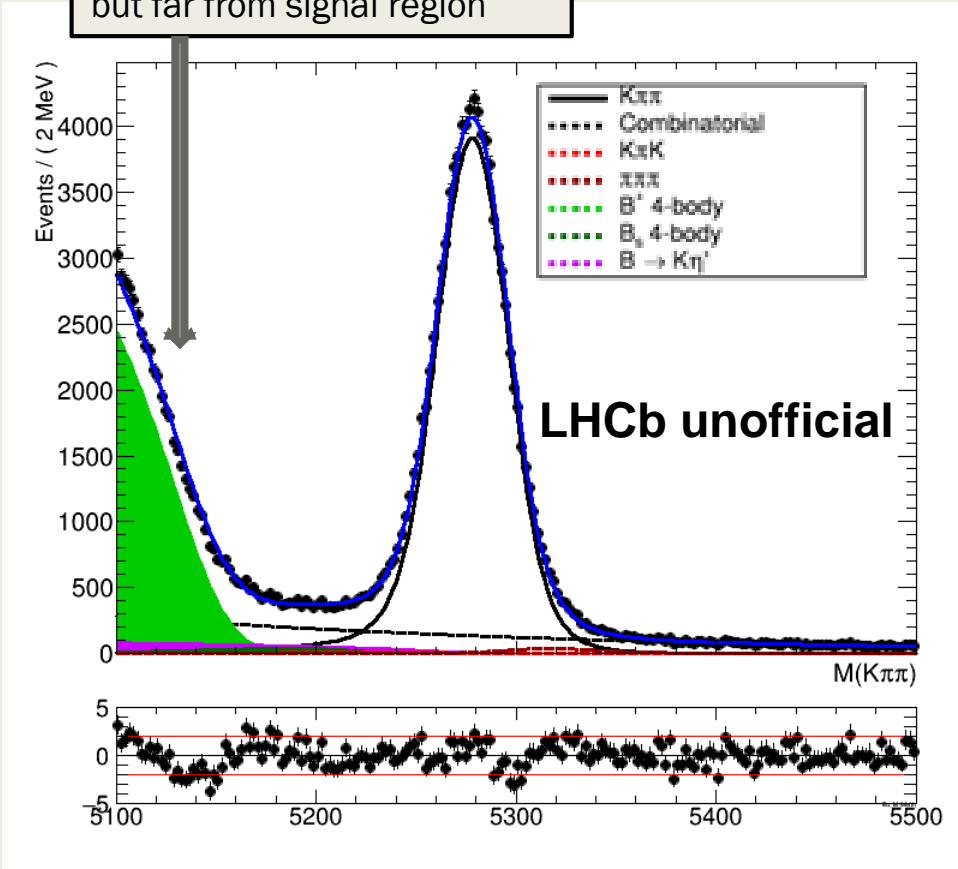
- Cross-feed yields are constrained by misID efficiencies



Simultaneous fit

Channel	Fit yield
KKK	68387 ± 310
πKK	7213 ± 160
$K\pi\pi$	93929 ± 409
$\pi\pi\pi$	24960 ± 223

Trend seen at low $K\pi\pi$ mass but far from signal region



Branching fraction ratios

- BF ratios given by (per event) efficiency-corrected yields: $\frac{BF(hhh)}{BF(KKK)} = \frac{N^{\text{corr}}(hhh)}{N^{\text{corr}}(KKK)}$
 - Background subtraction done using the *sPlot* technique
 - $N^{\text{corr}} = \sum_i \frac{w_i}{\epsilon_i} + \text{correction due to constrained cross-feed yields } (w_i = \text{event sWeight})$

- Ratios are consistent with ratios using PDG values:
 - Statistical uncertainties considerably improved compared to PDG
 - Results are likely to be systematically limited

LHCb unofficial	PDG ratio	Measured ratio
$BF(\pi KK)/BF(KKK)$	0.147 ± 0.021	0.1406 ± 0.0034 (stat)
$BF(K\pi\pi)/BF(KKK)$	1.50 ± 0.11	1.738 ± 0.013 (stat)
$BF(\pi\pi\pi)/BF(KKK)$	0.447 ± 0.045	0.5052 ± 0.0054 (stat)

Sources of systematics

- Fit model:
 - Choice of model – try alternative PDFs
 - Fixed parameters – vary within uncertainties
 - Fit bias – check with toys
- Finite MC statistics
- Event selection:
 - Data/MC discrepancies
 - Veto windows
- Efficiencies:
 - Trigger, tracking corrections

Summary

- Selection strategy finalised for both runs
- Simultaneous fit to Run 1 is in good shape
 - Run 2 fit being worked on
- Preliminary results consistent with PDG
 - Potential significant improvement in precision
- Towards completion:
 - Calculate systematic uncertainties
 - Measure Run 2 ratios

Backup

Branching fraction ratios

PDG ratios

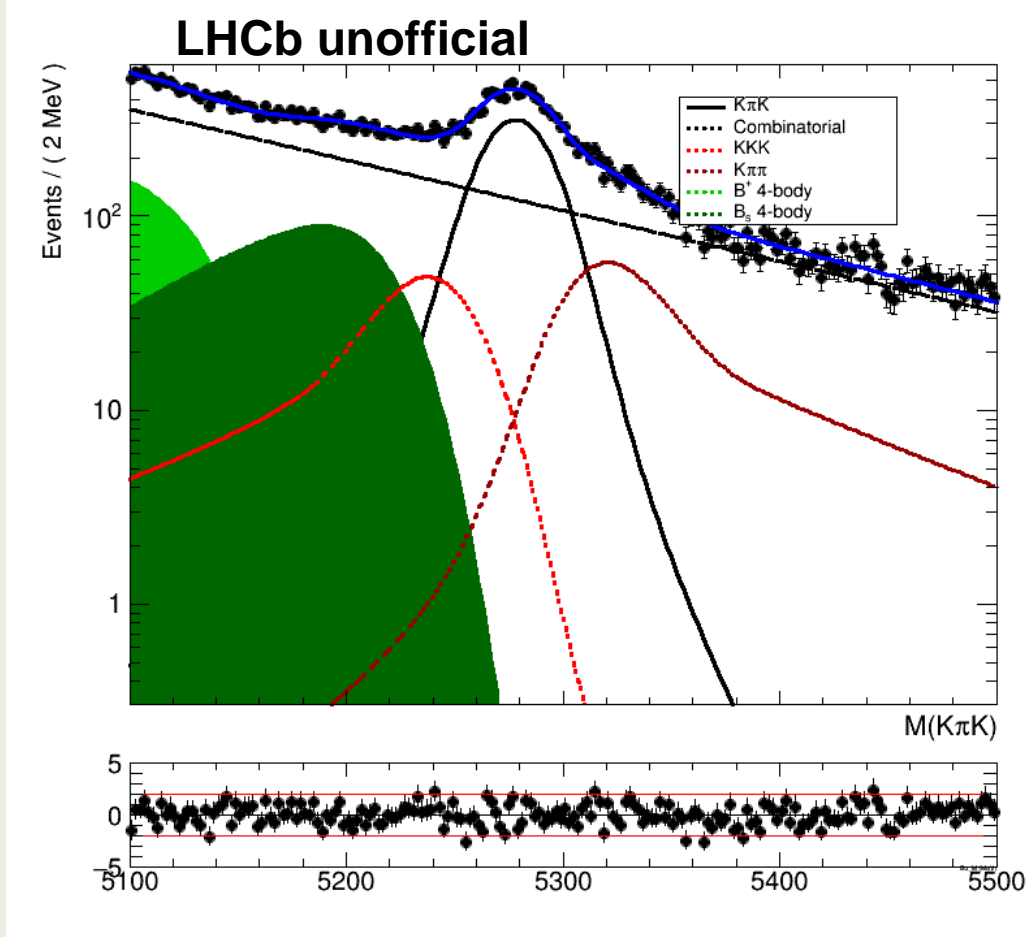
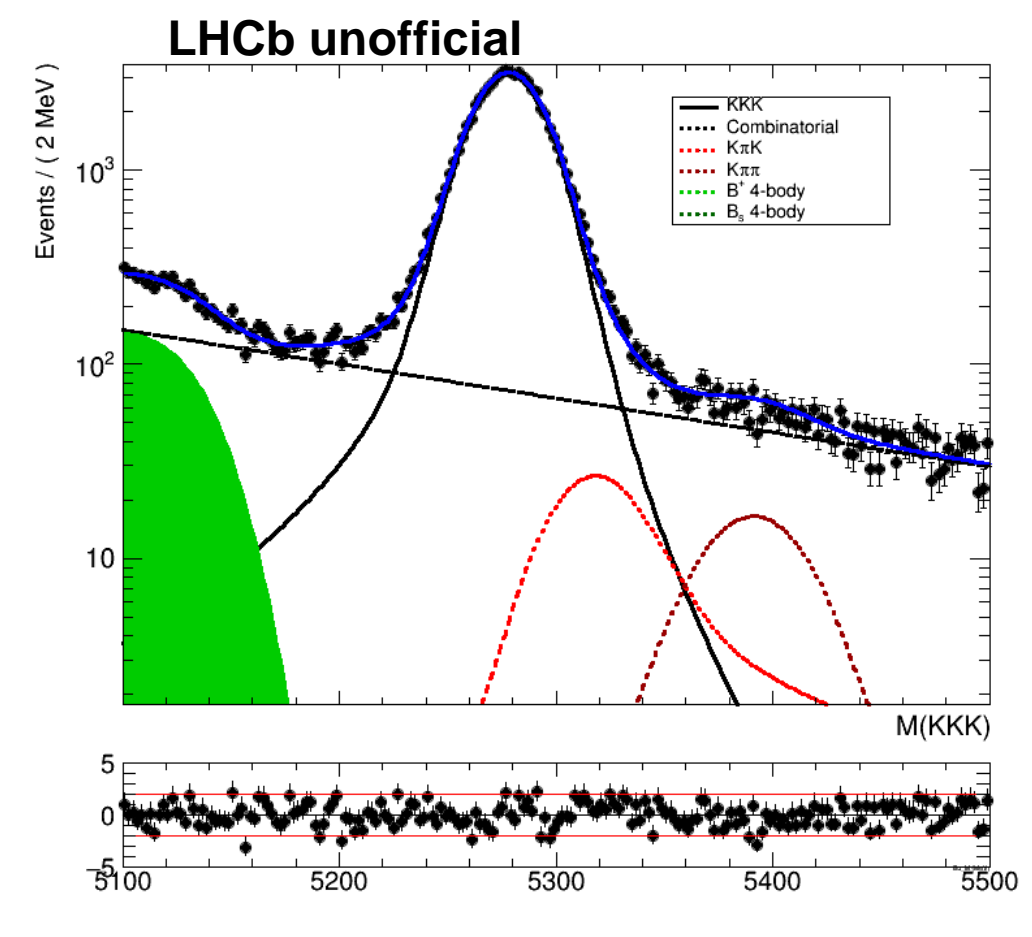
<i>row/col</i>	KKK	$K\pi K$	$K\pi\pi$	$\pi\pi\pi$
KKK	1	6.80 ± 0.99	0.667 ± 0.047	2.24 ± 0.23
$K\pi K$	0.147 ± 0.021	1	0.098 ± 0.015	0.329 ± 0.055
$K\pi\pi$	1.50 ± 0.11	10.2 ± 1.5	1	3.36 ± 0.36
$\pi\pi\pi$	0.447 ± 0.045	3.04 ± 0.51	0.298 ± 0.032	1

Measured ratios (stat uncertainties only)

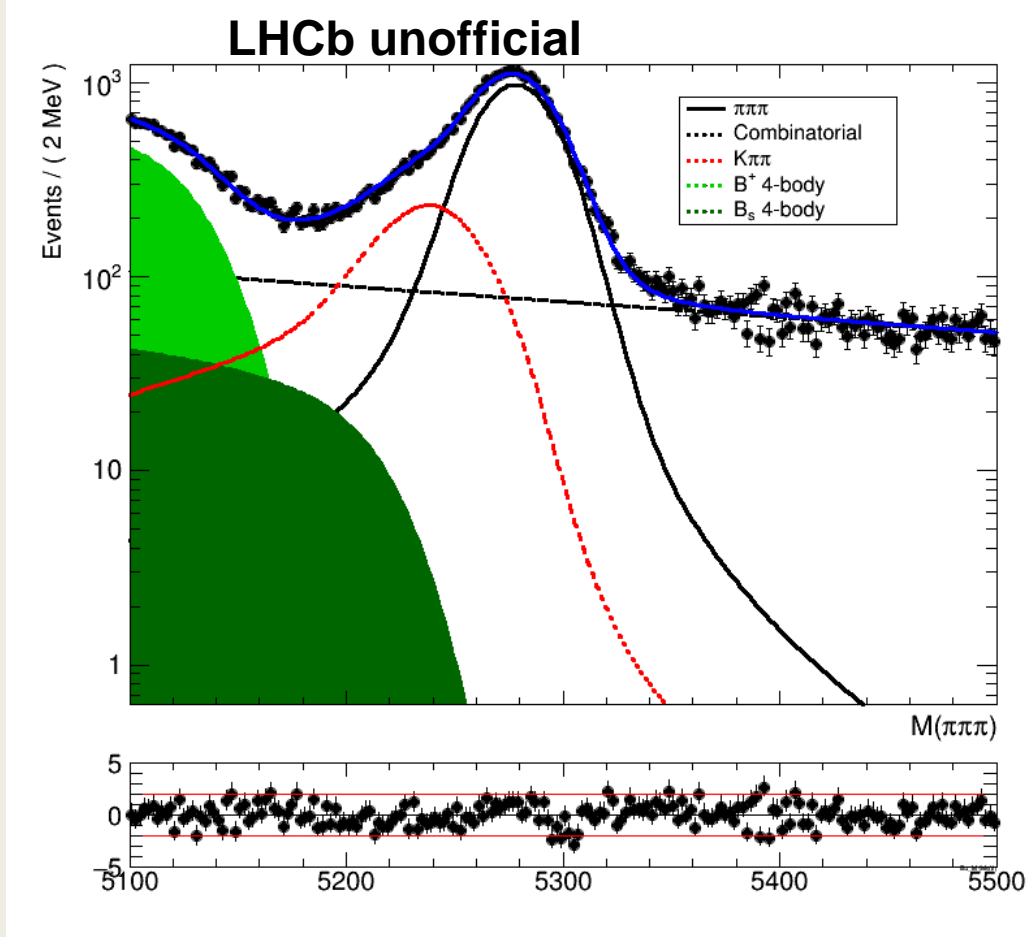
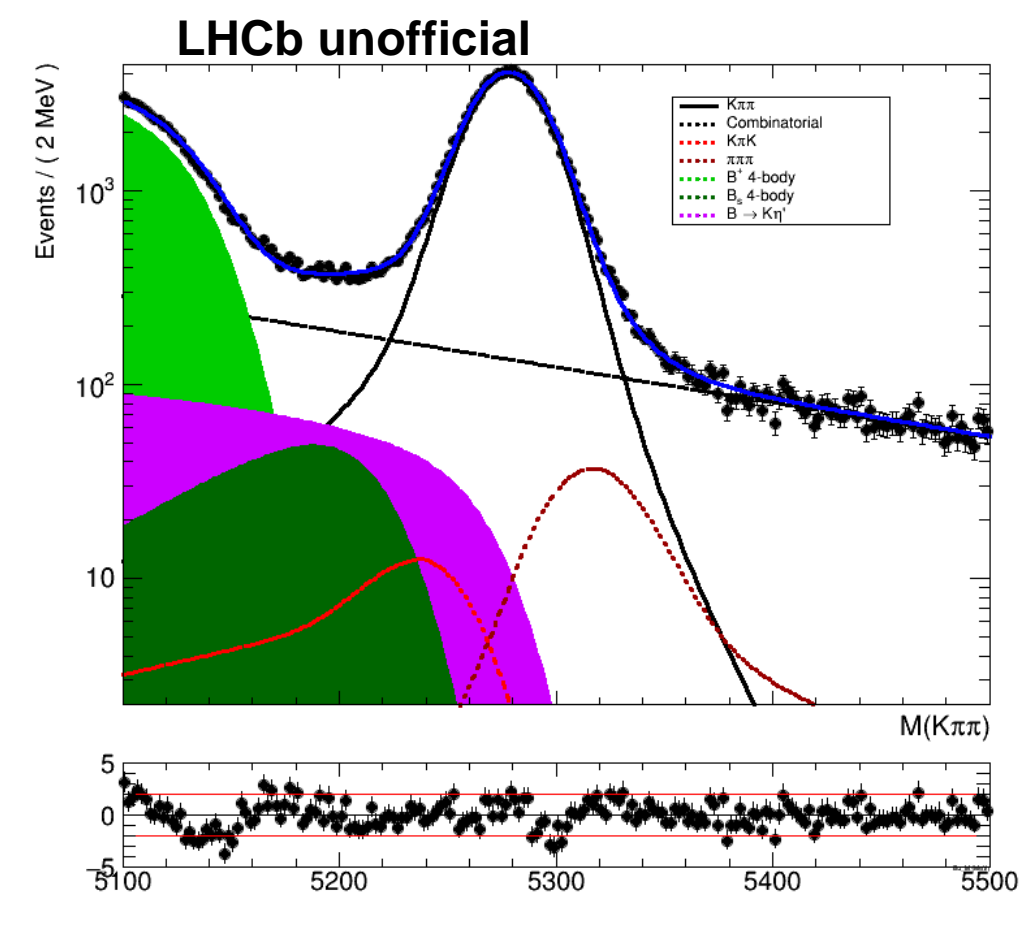
LHCb unofficial

<i>row/col</i>	KKK	$K\pi K$	$K\pi\pi$	$\pi\pi\pi$
KKK	1	7.11 ± 0.17	0.5755 ± 0.0044	1.980 ± 0.021
$K\pi K$	0.1406 ± 0.0034	1	0.0809 ± 0.0020	0.2783 ± 0.0071
$K\pi\pi$	1.738 ± 0.013	12.36 ± 0.30	1	3.440 ± 0.039
$\pi\pi\pi$	0.5052 ± 0.0054	3.594 ± 0.092	0.2907 ± 0.0033	1

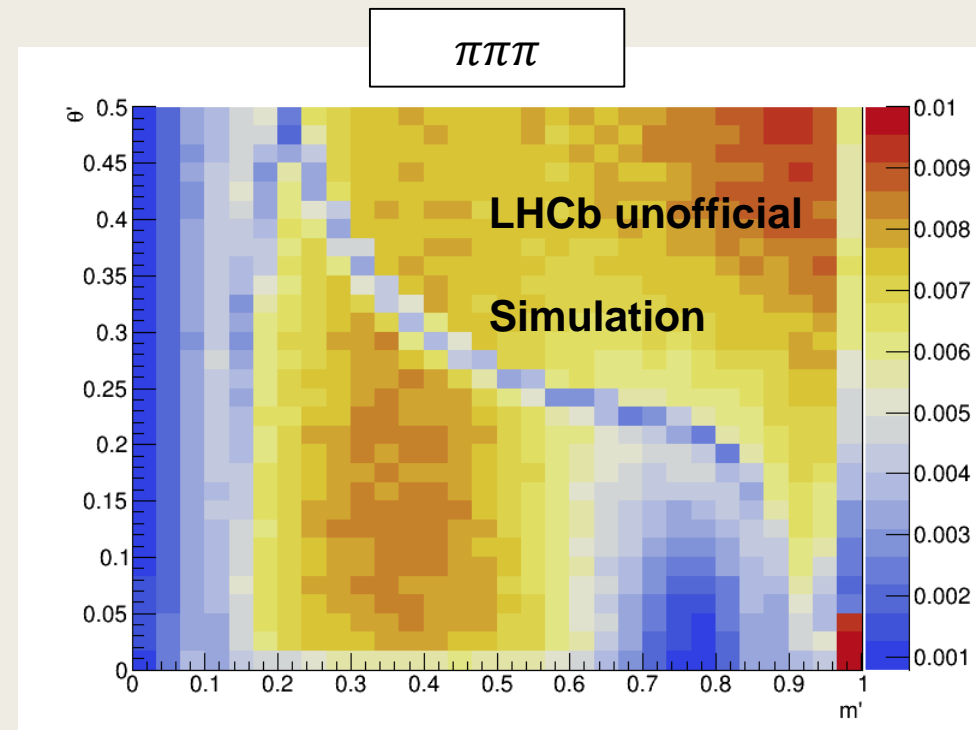
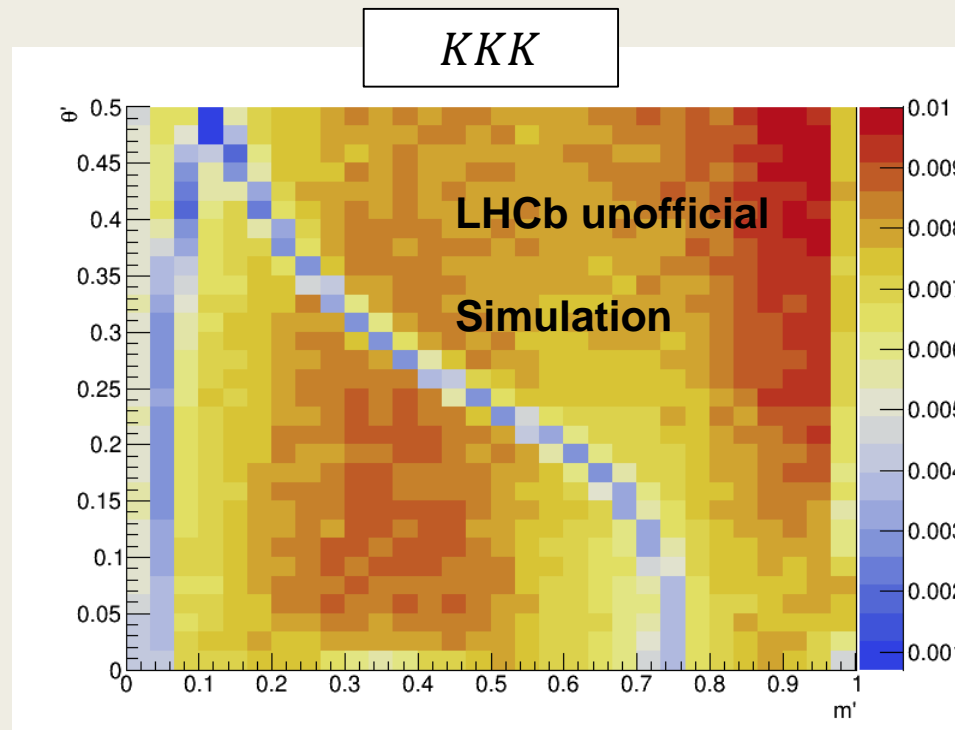
Simultaneous fit – log



Simultaneous fit – log



Efficiencies



Efficiencies

